

**CN74F109-X REV 1A0**

Original Creation Date: 11/14/96  
Last Update Date: 06/19/97  
Last Major Revision Date: 04/17/97

**DUAL JK POSITIVE EDGE-TRIGGERED FLIP-FLOP**

**General Description**

The F109 consists of two high-speed, completely independent transition clocked JK flip-flops. The clocking operation is independent of rise and fall times of the clock waveform. The JK design allows operation as a D flip-flop (refer to F74 data sheet) by connecting the J and K inputs.

**Asynchronous Inputs:**

- LOW input to  $\overline{SD}$  sets Q to HIGH level
- LOW input to  $\overline{CD}$  sets Q to LOW level
- Clear and Set are independent of clock
- Simultaneous LOW on  $\overline{CD}$  and  $\overline{SD}$  makes both Q and  $\overline{Q}$  HIGH

**Industry Part Number**

74F109

**NS Part Numbers**

74F109DC

**Prime Die**

M109

**Processing**

**Quality Conformance Inspection**

Subgrp	Description	Temp ( °C)
1	Static tests at	+25
2	Static tests at	+70
3	Static tests at	0
4	Dynamic tests at	+25
5	Dynamic tests at	+70
6	Dynamic tests at	0
7	Functional tests at	+25
8A	Functional tests at	+70
8B	Functional tests at	0
9	Switching tests at	+25
10	Switching tests at	+70
11	Switching tests at	0

**Features**

- Guaranteed 4000V minimum ESD protection.

**(Absolute Maximum Ratings)**

(Note 1)

Storage Temperature	-65 C to +150 C
Ambient Temperature under Bias	-55 C to +125 C
Junction Temperature under Bias	-55 C to +175 C
Vcc Pin Potential to Ground Pin	-0.5V to +7.0V
Input Voltage (Note 2)	-0.5V to +7.0V
Input Current (Note 2)	-30 mA to +5.0mA
Voltage Applied to Output in HIGH State (with Vcc=0V)	
Standard Output	-0.5V to Vcc
TRI-STATE Output	-0.5V to +5.5V
Current Applied to Output in LOW State (Max)	twice the rated Iol(mA)
ESD Last Passing Voltage (Min)	4000V

Note 1: Absolute Maximum ratings are those values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

Note 2: Either voltage limit or current limit is sufficient to protect inputs.

**Recommended Operating Conditions**

Free Air Ambient Temperature Commercial	0 C to +70 C
Supply Voltage Commercial	+4.5V to +5.5V

## Electrical Characteristics

### DC PARAMETER

(The following conditions apply to all the following parameters, unless otherwise specified.)  
DC: VCC 4.5V to 5.5V, Temp range: 0C to +70C

SYMBOL	PARAMETER	CONDITIONS	NOTES	PIN-NAME	MIN	MAX	UNIT	SUB-GROUPS
VIH	Input HIGH Voltage	Recognized as a HIGH Signal	1	INPUTS	2.0		V	1, 2, 3
VIL	Input LOW Voltage	Recognized as a LOW Signal	1	INPUTS		0.8	V	1, 2, 3
VCD	Input Clamp Diode Voltage	VCC=4.5V, IIN=-18mA	2, 3	INPUTS		-1.2	V	1, 2, 3
VOH	Output HIGH Voltage	VCC=4.5V, IOH=-1.0mA	2, 3	OUTPUTS	2.5		V	1, 2, 3
		VCC=4.75V, IOH=-1.0mA	2, 3	OUTPUTS	2.7		V	1, 2, 3
VOL	Output LOW Voltage	VCC=4.5V, IOL=20mA	2, 3	OUTPUTS		0.5	V	1, 2, 3
IIH	Input HIGH Current	VCC=5.5V, VIN=2.7V	2, 3	INPUTS		5.0	uA	1, 2, 3
IBVI	Input HIGH Current Breakdown Test	VCC=5.5V, VIN=7.0V	2, 3	INPUTS		7.0	uA	1, 2, 3
ICEX	Output HIGH Leakage Current	VCC=5.5V, VOUT = VCC	2, 3	OUTPUTS		100	uA	1, 2, 3
VID	Input Leakage Test	VCC = 0.0V, IID = 1.9uA, All other pins grounded	2, 3	INPUTS	4.75		V	1, 2, 3
IOD	Output Leakage Circuit Current	VCC = 0.0V, VIOD = 150mV, All other pins grounded	2, 3	OUTPUTS		4.75	uA	1, 2, 3
IIL	Input LOW Current	VCC=5.5V, VIN=0.5V	2, 3	Jn, Kn		-0.6	mA	1, 2, 3
		VCC=5.5V, VIN = 0.5V	2, 3	CDn, SDn		-1.8	mA	1, 2, 3
IOS	Output Short Circuit Current	VCC=5.5V, VOUT = 0V	2, 3	OUTPUTS	-60	-150	mA	1, 2, 3
ICC	Power Supply Current	VCC=5.5V, CP = 0V	2, 3	VCC		17.0	mA	1, 2, 3

## Electrical Characteristics

### AC PARAMETER

(The following conditions apply to all the following parameters, unless otherwise specified.)  
AC: CL=50pf, RL=500 OHMS, TR=2.5ns, TF=2.5ns, SEE AC FIGS. Temp Range: 0C to +70C

SYMBOL	PARAMETER	CONDITIONS	NOTES	PIN-NAME	MIN	MAX	UNIT	SUB-GROUPS
fMAX	Maximum Clock Frequency	VCC=+5.0V @ +25C, VCC=4.5V & 5.5V @ 0/+70C	4		100		MHZ	9
			4		90		MHZ	10, 11
tpLH(1)	Propagation Delay	VCC=+5.0V @ +25C, VCC=4.5V & 5.5V @ 0/+70C	2, 3	CPn to Qn/ $\bar{Q}$ n	3.8	7.0	ns	9
			2, 3	CPn to Qn/ $\bar{Q}$ n	3.8	8.0	ns	10, 11
tpHL(1)	Propagation Delay	VCC=+5.0V @ +25C, VCC=4.5V & 5.5V @ 0/+70C	2, 3	CPn to Qn/ $\bar{Q}$ n	4.4	8.0	ns	9
			2, 3	CPn to Qn/ $\bar{Q}$ n	4.4	9.2	ns	10, 11
tpLH(2)	Propagation Delay CDn/ $\bar{S}$ Dn to Qn/ $\bar{Q}$ n	VCC=+5.0V @ +25C, VCC=4.5V & 5.5V @ 0/+70C	2, 3		3.2	7.0	ns	9
tpLH(2)	Propagation Delay CDn/ $\bar{S}$ Dn to Qn/ $\bar{Q}$ n	VCC=+5.0V @ +25C, VCC=4.5V & 5.5V @ 0/+70C	2, 3		3.2	8.0	ns	10, 11
tpHL(2)	Propagation Delay CDn/ $\bar{S}$ Dn to Qn/ $\bar{Q}$ n	VCC=+5.0V @ +25C, VCC=4.5V & 5.5V @ 0/+70C	2, 3		3.5	9.0	ns	9
tpHL(2)	Propagation Delay CDn/ $\bar{S}$ Dn to Qn/ $\bar{Q}$ n	VCC=+5.0V @ +25C, VCC=4.5V & 5.5V @ 0/+70C	2, 3		3.5	10.5	ns	10, 11
ts(H)	Setup Time (HIGH)	VCC=+5.0V @ +25C, VCC=4.5V & 5.5V @ 0/+70C	4	Jn/ $\bar{K}$ n to CPn	3.0		ns	9, 10, 11
ts(L)	Setup Time (LOW)	VCC=+5.0V @ +25C, VCC=4.5V & 5.5V @ 0/+70C	4	Jn/ $\bar{K}$ n to CPn	3.0		ns	9, 10, 11
th(H/L)	Hold Time (HIGH or LOW)	VCC=+5.0V @ +25C, VCC=4.5V & 5.5V @ 0/+70C	4	Jn/ $\bar{K}$ n to CPn	1.0		ns	9, 10, 11
tw(H)	Pulse Width (HIGH)	VCC=+5.0V @ +25C, VCC=4.5V & 5.5V @ 0/+70C	4	CPn	4.0		ns	9, 10, 11
tw(L)	Pulse Width (LOW)	VCC=+5.0V @ +25C, VCC=4.5V & 5.5V @ 0/+70C	4	CPn	5.0		ns	9, 10, 11
tw (L)	Pulse Width (LOW)	VCC=+5.0V @ +25C, VCC=4.5V & 5.5V @ 0/+70C	4	$\bar{C}$ Dn or $\bar{S}$ Dn	4.0		ns	9, 10, 11
tREC	Recovery Time	VCC=+5.0V @ +25C, VCC=4.5V & 5.5V @ 0/+70C	4	$\bar{C}$ Dn/ $\bar{S}$ Dn to CP	2.0		ns	9, 10, 11

Note 1: Guaranteed by applying specific input condition and testing VOL & VOH.

Note 2: Screen tested 100% on each device at +75C temperature only, subgroups A2 & A10.

Note 3: Sample tested (Method 5005, table 1) on each MFG. lot at +75C temperature only, subgroups A2 & A10.

Note 4: Guaranteed but not tested.

### Revision History

Rev	ECN #	Rel Date	Originator	Changes
1A0	M0001343	06/19/97	Donald B. Miller	